## Paul M Voyles

List of Publications by Year in descending order

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219 papers 6,198 citations

66343 42 h-index 72 g-index

227 all docs

227 docs citations

times ranked

227

7062 citing authors

#	Article	IF	CITATIONS
1	Correlation symmetry analysis of electron nanodiffraction from amorphous materials. Ultramicroscopy, 2022, 232, 113405.	1.9	7
2	Optimizing mechanical properties in single-layered and multi-layered amorphous carbon coatings. Diamond and Related Materials, 2022, 123, 108843.	3.9	2
3	Surface Diffusion Is Controlled by Bulk Fragility across All Glass Types. Physical Review Letters, 2022, 128, 075501.	7.8	13
4	Machine Learning Prediction of the Critical Cooling Rate for Metallic Glasses from Expanded Datasets and Elemental Features. Chemistry of Materials, 2022, 34, 2945-2954.	6.7	9
5	Machine learning in scanning transmission electron microscopy. Nature Reviews Methods Primers, 2022, 2, .	21.2	59
6	Structural tunability and origin of two-level systems in amorphous silicon. Physical Review Materials, 2022, 6, .	2.4	1
7	Varying kinetic stability, icosahedral ordering, and mechanical properties of a model Zr-Cu-Al metallic glass by sputtering. Physical Review Materials, 2021, 5, .	2.4	3
8	Atomic structure of a glass imaged at last. Nature, 2021, 592, 31-32.	27.8	4
9	Factors correlating to enhanced surface diffusion in metallic glasses. Journal of Chemical Physics, 2021, 154, 104502.	3.0	6
10	Epitaxy, exfoliation, and strain-induced magnetism in rippled Heusler membranes. Nature Communications, 2021, 12, 2494.	12.8	25
11	Mechanisms of bulk and surface diffusion in metallic glasses determined from molecular dynamics simulations. Acta Materialia, 2021, 209, 116794.	7.9	20
12	Fast Surface Dynamics on a Metallic Glass Nanowire. ACS Nano, 2021, 15, 11309-11316.	14.6	15
13	An Ultrafast Direct Electron Camera for 4D STEM. Microscopy and Microanalysis, 2021, 27, 1004-1006.	0.4	11
14	Benchmark tests of atom-locating CNN models with a consistent dataset. Microscopy and Microanalysis, 2021, 27, 2518-2520.	0.4	2
15	Oxidation of metallic glass thin films: a combined EPMA and XPS investigation into the composition and thickness of oxidized surfaces. Microscopy and Microanalysis, 2021, 27, 3328-3330.	0.4	0
16	Symmetry Analysis in Metallic Glasses by Electron Nanodiffraction. Microscopy and Microanalysis, 2021, 27, 748-752.	0.4	0
17	Exploration of characteristic temperature contributions to metallic glass forming ability. Computational Materials Science, 2021, 196, 110494.	3.0	6
18	Molecular simulation-derived features for machine learning predictions of metal glass forming ability. Computational Materials Science, 2021, 199, 110728.	3.0	5

#	Article	IF	CITATIONS
19	Optimizing Nonrigid Registration for Scanning Transmission Electron Microscopy Image Series. Microscopy and Microanalysis, 2021, 27, 90-98.	0.4	3
20	Graph network based deep learning of bandgaps. Journal of Chemical Physics, 2021, 155, 154702.	3.0	12
21	Structure and magnetism in epitaxial <mml:math xmlns:mml="http://www.w3.org/1998/Math/MathML"><mml:msub><mml:mrow><mml:mi>Fe</mml:mi><td>mr<b>ow</b>+&gt; &lt; mi</td><td>ml<b>:</b>2mrow&gt;<m< td=""></m<></td></mml:mrow></mml:msub></mml:math>	mr <b>ow</b> +> < mi	ml <b>:</b> 2mrow> <m< td=""></m<>
22	Reentrant glass transition leading to ultrastable metallic glass. Materials Today, 2020, 34, 66-77.	14.2	45
23	Atomic resolution convergent beam electron diffraction analysis using convolutional neural networks. Ultramicroscopy, 2020, 210, 112921.	1.9	26
24	Denoising atomic resolution 4D scanning transmission electron microscopy data with tensor singular value decomposition. Ultramicroscopy, 2020, 219, 113123.	1.9	21
25	Supertwisted spirals of layered materials enabled by growth on non-Euclidean surfaces. Science, 2020, 370, 442-445.	12.6	65
26	Control of polymorphism during epitaxial growth of hyperferroelectric candidate LiZnSb on GaSb (111)B. Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics, 2020, 38, .	1.2	9
27	"Crystallography―of an Amorphous Material Using Electron Nanodiffraction. Microscopy and Microanalysis, 2020, 26, 38-40.	0.4	0
28	Structural Determination in Metallic Glasses from Correlations in 4D STEM Datasets. Microscopy and Microanalysis, 2020, 26, 940-942.	0.4	1
29	Electron Correlation Microscopy Measurements of Metallic Glass Surface Dynamics. Microscopy and Microanalysis, 2020, 26, 1142-1143.	0.4	0
30	Denoising Atomic Resolution Hyperspectral Data with Tensor Singular Value Decomposition. Microscopy and Microanalysis, 2020, 26, 1722-1723.	0.4	0
31	Superconductivity and fluctuation effects in a fractal dimensional bulk metallic glass: Correlation with medium range order. Materials Today Communications, 2020, 25, 101427.	1.9	3
32	Memristive Behavior Enabled by Amorphous–Crystalline 2D Oxide Heterostructure. Advanced Materials, 2020, 32, e2000801.	21.0	26
33	Radiation-induced segregation in a ceramic. Nature Materials, 2020, 19, 992-998.	27.5	47
34	Semi-adsorption-controlled growth window for half-Heusler FeVSb epitaxial films. Physical Review Materials, 2020, 4, .	2.4	7
35	4D Scanning Transmission Electron Microscopy of a Twisted WS2 Multilayer Structure. Microscopy and Microanalysis, 2020, 26, 628-630.	0.4	0
36	Electron Correlation Microscopy for Studying Fluctuating Systems In Situ. Microscopy and Microanalysis, 2019, 25, 1520-1521.	0.4	0

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37	Bioinspired Synthesis of Quasi-Two-Dimensional Monocrystalline Oxides. Chemistry of Materials, 2019, 31, 9040-9048.	6.7	21
38	Effectively Synchronizing 4D-STEM Detectors with Probe Movement. Microscopy and Microanalysis, 2019, 25, 68-69.	0.4	0
39	Atomic Resolution Convergent Beam Electron Diffraction Analysis Using Convolutional Neural Networks. Microscopy and Microanalysis, 2019, 25, 128-129.	0.4	1
40	Enhanced Ferromagnetism from Organic–Cerium Oxide Hybrid Ultrathin Nanosheets. ACS Applied Materials & Date (1997) (1998) (19	8.0	8
41	Microstructure and microchemistry study of irradiation-induced precipitates in proton irradiated ZrNb alloys. Acta Materialia, 2019, 178, 228-240.	7.9	33
42	Short-range order structure motifs learned from an atomistic model of a Zr50Cu45Al5 metallic glass. Acta Materialia, 2019, 175, 35-45.	7.9	29
43	Heavyâ€Metalâ€Free, Lowâ€Damping, and Nonâ€Interface Perpendicular Fe 16 N 2 Thin Film and Magnetoresistance Device. Physica Status Solidi - Rapid Research Letters, 2019, 13, 1900089.	2.4	12
44	Effect of Mo capping in sub-100†nm CoFeB-MgO tunnel junctions with perpendicular magnetic anisotropy. Journal of Magnetism and Magnetic Materials, 2019, 483, 34-41.	2.3	1
45	High electrical conductivity in the epitaxial polar metals LaAuGe and LaPtSb. APL Materials, 2019, 7, .	5.1	15
46	StructOpt: A modular materials structure optimization suite incorporating experimental data and simulated energies. Computational Materials Science, 2019, 160, 1-8.	3.0	7
47	Electronically enhanced layer buckling and Au-Au dimerization in epitaxial LaAuSb films. Physical Review Materials, 2019, 3, .	2.4	5
48	<mml:math <="" p="" xmlns:mml="http://www.w3.org/1998/Math/MathML"> display="inline"&gt;<mml:mrow><mml:msub><mml:mrow><mml:mi>L</mml:mi><mml:mi><mml:mn>1</mml:mn></mml:mi></mml:mrow><mml:mrow><mml:mi>L</mml:mi><mml:mi><mml:mn>1 Synthetic Antiferromagnet through an fcc Ru Spacer Utilized for Perpendicular Magnetic Tunnel Junctions. Physical Review Applied, 2018, 9, .</mml:mn></mml:mi></mml:mrow></mml:msub></mml:mrow></mml:math>	ow <sub>}.{</sub> mml:	mrogw> <mml< td=""></mml<>
49	Vitrification, crystallization, and atomic structure of deformed and quenched Ni60Nb40 metallic glass. Journal of Non-Crystalline Solids, 2018, 491, 133-140.	3.1	13
50	Reduced interface spin polarization by antiferromagnetically coupled Mn segregated to the <mml:math xmlns:mml="http://www.w3.org/1998/Math/MathML"><mml:mrow><mml:mi mathvariant="normal">C</mml:mi><mml:msub><mml:mi mathvariant="normal">o</mml:mi><mml:mn></mml:mn></mml:msub><mml:mi>MnSi</mml:mi><mml:mrow></mml:mrow></mml:mrow></mml:math>	3.2 · <td>10 ath&gt;</td>	10 ath>
51	/GaAs (001) interface. Physical Review B, 2018, 97, . Ionic Layer Epitaxy of Nanometer-Thick Palladium Nanosheets with Enhanced Electrocatalytic Properties. Chemistry of Materials, 2018, 30, 3308-3314.	6.7	29
52	H <sub>2</sub> V <sub>3</sub> O <sub>8</sub> Nanowire/Graphene Electrodes for Aqueous Rechargeable Zinc Ion Batteries with High Rate Capability and Large Capacity. Advanced Energy Materials, 2018, 8, 1800144.	19.5	427
53	Spatially heterogeneous dynamics in a metallic glass forming liquid imaged by electron correlation microscopy. Nature Communications, 2018, 9, 1129.	12.8	73
54	In situ Transmission Electron Microscopy of Room-temperature Plastic Deformation and Recovery in Thin 3C-SiC. Microscopy and Microanalysis, 2018, 24, 1834-1835.	0.4	0

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55	Surface Gradient Ti-Doped MnO <sub>2</sub> Nanowires for High-Rate and Long-Life Lithium Battery. ACS Applied Materials & Diterfaces, 2018, 10, 44376-44384.	8.0	41
56	Paths to Stabilizing Electronically Aberrant Compounds: A Defect-Stabilized Polymorph and Constrained Atomic Motion in PtGa2. Inorganic Chemistry, 2018, 57, 13880-13894.	4.0	7
57	Demonstration of Ru as the 4th ferromagnetic element at room temperature. Nature Communications, 2018, 9, 2058.	12.8	29
58	Metastable Intermediates in Amorphous Titanium Oxide: A Hidden Role Leading to Ultra-Stable Photoanode Protection. Nano Letters, 2018, 18, 5335-5342.	9.1	36
59	Materials Design of Glasses. Current Opinion in Solid State and Materials Science, 2018, 22, 39-40.	11.5	1
60	FEMSIM +ÂHRMC: Simulation of and structural refinement using fluctuation electron microscopy for amorphous materials. Computer Physics Communications, 2017, 213, 217-222.	7.5	8
61	Perpendicular magnetic tunnel junction with W seed and capping layers. Journal of Applied Physics, 2017, 121, .	2.5	21
62	Informatics and data science in materials microscopy. Current Opinion in Solid State and Materials Science, 2017, 21, 141-158.	11.5	33
63	Tm <sub>3</sub> Fe <sub>5</sub> O <sub>12</sub> /Pt Heterostructures with Perpendicular Magnetic Anisotropy for Spintronic Applications. Advanced Electronic Materials, 2017, 3, 1600376.	5.1	112
64	Measurement of Irradiation-induced Swelling in Stainless Steels with a New Transmission Electron Microscopy Method. Microscopy and Microanalysis, 2017, 23, 2234-2235.	0.4	0
65	Identification and Quantification of Boron Dopant Sites in Antiferromagnetic Cr2O3 Films by Electron Energy Loss Spectroscopy. Microscopy and Microanalysis, 2017, 23, 1584-1585.	0.4	2
66	Electrical Control of Metallic Heavy-Metal–Ferromagnet Interfacial States. Physical Review Applied, 2017, 8, .	3.8	19
67	Local Dielectric Breakdown Path along <i>c</i> àâ€Axis Planar Boundaries in Cr <sub>2</sub> O <sub>3</sub> Thin Films. Advanced Materials Interfaces, 2017, 4, 1700172.	3.7	12
68	Atomic-scale Relaxation Dynamics in the Supercooled Liquid State of a Metallic Glass Nanowire by Electron Correlation Microscopy. Microscopy and Microanalysis, 2017, 23, 960-961.	0.4	0
69	Effect of tungsten alloying on short-to-medium-range-order evolution and crystallization behavior of near-eutectic amorphous Ni–P. Acta Materialia, 2017, 122, 400-411.	7.9	13
70	Applications and limitations of electron correlation microscopy to study relaxation dynamics in supercooled liquids. Ultramicroscopy, 2017, 178, 125-130.	1.9	11
71	Dielectric breakdown along c-axis boundaries in magnetoelectric O2O3 for spintronic devices. Microscopy and Microanalysis, 2017, 23, 1442-1443.	0.4	0
72	Bayesian Statistical Model for Imaging of Single La Vacancies in LaMnO3. Microscopy and Microanalysis, 2017, 23, 1572-1573.	0.4	2

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73	Joint Denoising and Distortion Correction for Atomic Column Detection in Scanning Transmission Electron Microscopy Images. Microscopy and Microanalysis, 2017, 23, 164-165.	0.4	3
74	Applications of High Precision STEM Imaging to Structurally Complex Materials. Microscopy and Microanalysis, 2017, 23, 418-419.	0.4	1
75	Combining Non-Rigid Registration with Non-Local Principle Component Analysis for Atomic Resolution EDS Mapping. Microscopy and Microanalysis, 2016, 22, 1406-1407.	0.4	O
76	Three-Dimensional Imaging of Single La Vacancies in LaMnO 3. Microscopy and Microanalysis, 2016, 22, 902-903.	0.4	2
77	Fluctuation Electron Microscopy and Computational Structure Refinement for the Structure of Amorphous Materials. Microscopy and Microanalysis, 2016, 22, 486-487.	0.4	1
78	Spin injection and detection up to room temperature in Heusler alloy/ <mml:math xmlns:mml="http://www.w3.org/1998/Math/MathML"><mml:mrow><mml:mi>n</mml:mi></mml:mrow><td>ath2-GaAs</td><td>s 49</td></mml:math>	ath2-GaAs	s 49
79	High-precision stress mapping and defect characterization of thin films of LaMnO 3 grown on DyScO 3 substrate Microscopy and Microanalysis, 2016, 22, 1526-1527.	0.4	O
80	Patterning of sub-50 nm perpendicular CoFeB/MgO-based magnetic tunnel junctions. Nanotechnology, 2016, 27, 185302.	2.6	7
81	Domain configurations in Co/Pd and L1 <sub>0</sub> -FePt nanowire arrays with perpendicular magnetic anisotropy. Nanoscale, 2016, 8, 5358-5367.	5.6	9
82	Integrated Computational and Experimental Structure Refinement for Nanoparticles. ACS Nano, 2016, 10, 4031-4038.	14.6	25
83	Non-rigid registration and non-local principle component analysis to improve electron microscopy spectrum images. Nanotechnology, 2016, 27, 364001.	2.6	30
84	Radiation-induced mobility of small defect clusters in covalent materials. Physical Review B, 2016, 94, .	3.2	10
85	Elastic and inelastic mean free paths of 200 keV electrons in metallic glasses. Ultramicroscopy, 2016, 171, 89-95.	1.9	8
86	Counterintuitive Reconstruction of the Polar O-Terminated ZnO Surface with Zinc Vacancies and Hydrogen. Journal of Physical Chemistry Letters, 2016, 7, 4483-4487.	4.6	19
87	Medium-range structure and glass forming ability in Zr–Cu–Al bulk metallic glasses. Acta Materialia, 2016, 109, 103-114.	7.9	76
88	Atomic Layer Epitaxy of h-BN(0001) Multilayers on Co(0001) and Molecular Beam Epitaxy Growth of Graphene on h-BN(0001)/Co(0001). Langmuir, 2016, 32, 2601-2607.	3.5	58
89	Electron Correlation Microscopy: A New Technique for Studying Local Atom Dynamics Applied to a Supercooled Liquid. Microscopy and Microanalysis, 2015, 21, 1026-1033.	0.4	21
90	Revealing New Atomic-scale Information about Materials by Improving the Quality and Quantifiability of Aberration-corrected STEM Data. Microscopy and Microanalysis, 2015, 21, 2409-2410.	0.4	0

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91	Thermal Resistance of Transferred-Silicon-Nanomembrane Interfaces. Physical Review Letters, 2015, 115, 256101.	7.8	28
92	Atomic Resolution Imaging of Black Spot Defects in Ion Irradiated Silicon Carbide. Microscopy and Microanalysis, 2015, 21, 1337-1338.	0.4	1
93	Prospects for Detecting Single Vacancies by Quantitative Scanning Transmission Electron Microscopy. Microscopy and Microanalysis, 2015, 21, 1887-1888.	0.4	0
94	Increased Fluctuation of Interatomic Distances in Distorted Structure of Stoichiometric LaMnO3. Microscopy and Microanalysis, 2015, 21, 2413-2414.	0.4	0
95	Networked Data Storage and Analysis for the Wisconsin Regional Materials Network. Microscopy and Microanalysis, 2015, 21, 371-372.	0.4	0
96	Integrated Computational and Experimental Structure Determination for Nanoparticles. Microscopy and Microanalysis, 2015, 21, 2201-2202.	0.4	0
97	Medium-Range Structure of Zr-Cu-Al Bulk Metallic Glasses from Structural Refinement Based on Fluctuation Microscopy. Microscopy and Microanalysis, 2015, 21, 1659-1660.	0.4	0
98	Influence of film composition in quaternary Heusler alloy Co <sub>2</sub> (Mn,Fe)Si thin films on tunnelling magnetoresistance of Co <sub>2</sub> (Mn,Fe)Si/MgO-based magnetic tunnel junctions. Journal Physics D: Applied Physics, 2015, 48, 164001.	2.8	88
99	High-precision scanning transmission electron microscopy at coarse pixel sampling for reduced electron dose. Advanced Structural and Chemical Imaging, 2015, 1, .	4.0	22
100	Poisson noise removal from high-resolution STEM images based on periodic block matching. Advanced Structural and Chemical Imaging, 2015, $1$ , .	4.0	32
101	Fluctuation Electron Microscopy Study of Medium-Range Packing Order in Ultrastable Indomethacin Glass Thin Films. Materials Research Society Symposia Proceedings, 2015, 1757, 32.	0.1	0
102	Quantitative Measurement of Density in a Shear Band of Metallic Glass Monitored Along its Propagation Direction. Physical Review Letters, 2015, 115, 035501.	7.8	110
103	Medium-range Order of Zr <sub>54</sub> Cu <sub>38</sub> Al <sub>8</sub> Bulk Metallic Glass. Materials Research Society Symposia Proceedings, 2014, 1649, 1.	0.1	3
104	Morphology of Amorphous Pockets in SiC Irradiated with 1 MeV Kr Ions. Microscopy and Microanalysis, 2014, 20, 1830-1831.	0.4	0
105	Effect of nonstoichiometry on the half-metallic character of Co2MnSi investigated through saturation magnetization and tunneling magnetoresistance ratio. Physical Review B, 2014, 89, .	3.2	42
106	Pore Structure and Bifunctional Catalyst Activity of Overlayers Applied by Atomic Layer Deposition on Copper Nanoparticles. ACS Catalysis, 2014, 4, 1554-1557.	11.2	58
107	Picometre-precision analysis of scanning transmission electron microscopy images of platinum nanocatalysts. Nature Communications, 2014, 5, 4155.	12.8	225
108	High-Resolution Scanning Transmission Electron Microscopy Study of Black Spot Defects in Ion Irradiated Silicon Carbide. Microscopy and Microanalysis, 2014, 20, 1824-1825.	0.4	3

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109	When is Z-Contrast D-Contrast?. Microscopy Today, 2014, 22, 65-65.	0.3	4
110	Thickness Variations and Absence of Lateral Compositional Fluctuations in Aberration-Corrected STEM Images of InGaN LED Active Regions at Low Dose. Microscopy and Microanalysis, 2014, 20, 864-868.	0.4	10
111	Precision Limits to STEM Imaging from Dynamical Scattering and Channeling of Sub-Angstrom Electron Probes. Microscopy and Microanalysis, 2014, 20, 120-121.	0.4	1
112	Fast flexible electronics with strained silicon nanomembranes. Scientific Reports, 2013, 3, 1291.	3.3	100
113	Inelastic and elastic mean free paths from FIB samples of metallic glasses. Ultramicroscopy, 2013, 124, 6-12.	1.9	13
114	Reactive sputtering of (Co,Fe) nitride thin films on TiN-bufferd Si. Applied Physics A: Materials Science and Processing, 2013, 110, 487-492.	2.3	5
115	Multiple Morphologies of Gold–Magnetite Heterostructure Nanoparticles are Effectively Functionalized with Protein for Cell Targeting. Microscopy and Microanalysis, 2013, 19, 821-834.	0.4	7
116	Rýcktitelbild: Stabilization of Copper Catalysts for Liquid-Phase Reactions by Atomic Layer Deposition (Angew. Chem. 51/2013). Angewandte Chemie, 2013, 125, 14068-14068.	2.0	1
117	Absence of Lateral Composition Fluctuations in Aberration-corrected STEM Images of an InGaN Quantum Well at Low Dose. Materials Research Society Symposia Proceedings, 2012, 1432, 73.	0.1	2
118	Impurity distribution and microstructure of Ga-doped ZnO films grown by molecular beam epitaxy. Journal of Applied Physics, 2012, 112, 123527.	2.5	13
119	Electron scattering mechanisms in GZO films grown on a-sapphire substrates by plasma-enhanced molecular beam epitaxy. Journal of Applied Physics, $2012,111,.$	2.5	38
120	Analytical and computational modeling of fluctuation electron microscopy from a nanocrystal/amorphous composite. Ultramicroscopy, 2012, 122, 37-47.	1.9	15
121	Stable p-Type Conduction from Sb-Decorated Head-to-Head Basal Plane Inversion Domain Boundaries in ZnO Nanowires. Nano Letters, 2012, 12, 1311-1316.	9.1	61
122	<title>Pyramid nano-voids in GaN and InGaN</title> ., 2012, , .		0
123	Electrical properties of ZnO:Ga as a transparent conducting oxide in InGaN based light emitting diodes. Proceedings of SPIE, 2012, , .	0.8	2
124	Hexagonal-based pyramid void defects in GaN and InGaN. Journal of Applied Physics, 2012, 111, .	2.5	14
125	Nanoscale Structure and Structural Relaxation in <mml:math display="inline" xmlns:mml="http://www.w3.org/1998/Math/MathML"><mml:msub><mml:mi>Zr</mml:mi><mml:mn>50</mml:mn></mml:msub><mml:msub><mml:msub><mml:r< td=""><td>ni&gt;Čå<td>ml:<del>167</del> &lt; mml:r</td></td></mml:r<></mml:msub></mml:msub></mml:math>	ni>Čå <td>ml:<del>167</del> &lt; mml:r</td>	ml: <del>167</del> < mml:r
126	Donor behavior of Sb in ZnO. Journal of Applied Physics, 2012, 112, 033706.	2.5	24

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127	Bifunctional Materials for the Catalytic Conversion of Cellulose into Soluble Renewable Biorefinery Feedstocks. Topics in Catalysis, 2012, 55, 148-161.	2.8	29
128	Local chemical and topological order in Al–Tb and its role in controlling nanocrystal formation. Acta Materialia, 2012, 60, 994-1003.	7.9	46
129	Inverse TMR in a nominally symmetric CoFe/AlOx/CoFe junction induced by interfacial Fe3O4 investigated by STEM-EELS. Journal of Magnetism and Magnetic Materials, 2012, 324, 1837-1844.	2.3	2
130	Behavior of Pt Atoms on Oxide Supports During Reduction Treatments at Elevated Temperatures, Characterized by Aberration Corrected Stem Imaging. Catalysis Letters, 2012, 142, 176-182.	2.6	46
131	Fluctuation Microscopy in the STEM. , 2011, , 725-756.		2
132	<jats:formula formulatype="inline"><jats:tex notation="TeX">\${m MgB}_{2}/{m MgO/MgB}_{2}\$</jats:tex></jats:formula> Josephson Junctions for High-Speed Circuits. IEEE Transactions on Applied Superconductivity, 2011, 21, 115-118.	1.7	10
133	Variable Resolution Fluctuation Electron Microscopy on Cu-Zr Metallic Glass Using a Wide Range of Coherent STEM Probe Size. Microscopy and Microanalysis, 2011, 17, 67-74.	0.4	60
134	Pre-Meeting Congress on Opportunities, Artifacts and Interpretation of Aberration-Corrected Electron Microscopy Data. Microscopy and Microanalysis, 2011, 17, 20-20.	0.4	0
135	Indium Composition Variation in Nominally Uniform InGaN Layers Discovered by Aberration-Corrected Z-contrast STEM. Microscopy and Microanalysis, 2011, 17, 1386-1387.	0.4	0
136	Vertical composition variation in nominally uniform InGaN layers revealed by aberration-corrected STEM imaging. Proceedings of SPIE, $2011,\ldots$	0.8	2
137	Epitaxial growth and thermal stability of Fe4N film on TiN buffered Si(001) substrate. Journal of Applied Physics, 2011, 109, 07E126.	2.5	15
138	Effect of sample thickness, energy filtering, and probe coherence on fluctuation electron microscopy experiments. Ultramicroscopy, 2011, 111, 1375-1380.	1.9	27
139	Optimization of ZnO:Ga properties for application as a transparent conducting oxide in InGaN-based light-emitting diodes. Proceedings of SPIE, 2011, , .	0.8	2
140	InGaN based light emitting diodes utilizing Ga doped ZnO as a highly transparent contact to pâ€GaN. Physica Status Solidi C: Current Topics in Solid State Physics, 2011, 8, 1548-1551.	0.8	12
141	High-field properties of carbon-doped MgB <sub>2</sub> thin films by hybrid physical–chemical vapor deposition using different carbon sources. Superconductor Science and Technology, 2011, 24, 125014.	3.5	21
142	Size analysis of nanoscale order in amorphous materials by variable-resolution fluctuation electron microscopy. Ultramicroscopy, 2010, 110, 1273-1278.	1.9	36
143	MgO platelets and high critical field in MgB2thin films doped with carbon from methane. Superconductor Science and Technology, 2010, 23, 049801-049801.	3.5	0
144	High-Jcâ€^MgB2 Josephson junctions with operating temperature up to 40 K. Applied Physics Letters, 2010, 96, .	3.3	27

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145	Epitaxial growth and magnetic properties of Fe3O4 films on TiN buffered Si(001), Si(110), and Si(111) substrates. Applied Physics Letters, 2010, 97, 092508.	3.3	34
146	Nanoscale disorder in pure and doped MgB $<$ sub $>$ 2 $<$ /sub $>$ thin films. Superconductor Science and Technology, 2010, 23, 095008.	3.5	13
147	Flexible formation of coherent probes on an aberration-corrected STEM with three condensers. Journal of Electron Microscopy, 2010, 59, S15-S21.	0.9	27
148	The Electron Microscopy Database: an Online Resource for Teaching and Learning Quantitative Transmission Electron Microscopy. Microscopy Today, 2009, 17, 26-27.	0.3	0
149	Flux Pinning Optimization of \${m MgB}_{2}\$ Bulk Samples Prepared Using High-Energy Ball Milling and Addition of \${m TaB}_{2}\$. IEEE Transactions on Applied Superconductivity, 2009, 19, 2797-2801.	1.7	16
150	MgO platelets and high critical field in MgB2thin films doped with carbon from methane. Superconductor Science and Technology, 2009, 22, 125001.	3 <b>.</b> 5	11
151	Effect of Growth Conditions on Structural and Electrical Properties of Ga-doped ZnO Films Grown by Plasma-assisted MBE. Materials Research Society Symposia Proceedings, 2009, 1201, 124.	0.1	0
152	Reverse Monte Carlo structural model for a zirconium-based metallic glass incorporating fluctuation microscopy medium-range order data. Journal of Materials Research, 2009, 24, 3121-3129.	2.6	23
153	Increased in-field critical current density in neutron-irradiated MgB <sub>2</sub> films. Superconductor Science and Technology, 2009, 22, 015023.	3 <b>.</b> 5	3
154	Effect of Doping on the Structural and Optical Properties of Microwave-Assisted Synthesis of ZnSe@ZnS Core-Shell Quantum Dots. Materials Research Society Symposia Proceedings, 2009, 1207, 1.	0.1	2
155	MnxZn1â^'xFe2â^'yRyO4 (R=Gd, Eu) ferrite nanocrystals for magnetocaloric applications. Microelectronics Journal, 2009, 40, 677-680.	2.0	28
156	Nanometer Scale Atomic Order in a Bulk Metallic Glass from Fluctuation Microscopy. Microscopy and Microanalysis, 2009, 15, 770-771.	0.4	0
157	A phenomenological model of fluctuation electron microscopy for a nanocrystal/amorphous composite. Ultramicroscopy, 2008, 108, 727-736.	1.9	45
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